ALPHA & OMEGA SEMICONDUCTOR

AOK60B65H2AL

650V, 60A AlphaIGBT™

With soft and fast recovery anti-parallel diode

General Description

- Latest AlphaIGBT (αIGBT) Technology
- 650V Breakdown voltage
- Very fast and soft recovery freewheeling diode
- High efficient turn-on di/dt controllability
- Very high switching speed
- Low Turn-Off switching loss and softness
- Very good EMI behavior

Applications

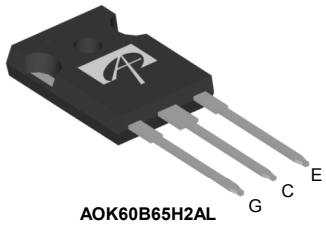
- Welding Machines
- UPS & Solar Inverters
- Very High Switching Frequency Applications

Product Summary

V_{CE}	650V
I_C (T_C=100°C)	60A
$V_{CE(sat)}$ (T_J=25°C)	1.95V

Green Product

TO-247



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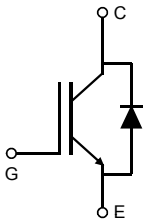

Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOK60B65H2AL	TO247	Tube	240

Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter		Symbol	AOK60B65H2AL	Units
Collector-Emitter Voltage		V_{CE}	650	V
Gate-Emitter Voltage		V_{GE}	±30	V
Continuous Collector Current	T_C=25°C	I_C	120	A
	T_C=100°C		60	
Pulsed Collector Current, Limited by T_{Jmax}		I_{CM}	180	A
Turn off SOA, V_{CE}≤650V, Limited by T_{Jmax}		I_{LM}	180	A
Continuous Diode Forward Current	T_C=25°C	I_F	60	A
	T_C=100°C		30	
Diode Pulsed Current, Limited by T_{Jmax}		I_{FM}	90	A
Power Dissipation	T_C=25°C	P_D	416	W
	T_C=100°C		166	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds		T_L	300	°C

Thermal Characteristics

Parameter	Symbol	Typical	Units
Maximum Junction-to-Ambient	$R_{\theta JA}$	40	°C/W
Maximum IGBT Junction-to-Case	$R_{\theta JC}$	0.3	°C/W
Maximum Diode Junction-to-Case	$R_{\theta JC}$	1.1	°C/W

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Typ	Max	Units
STATIC PARAMETERS							
BV_{CES}	Collector-Emitter Breakdown Voltage	I_C=1mA, V_{GE}=0V, T_J=25°C		650	-	-	V
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	V_{GE}=15V, I_C=60A	T_J=25°C	-	1.95	2.5	V
			T_J=125°C	-	2.45	-	
			T_J=150°C	-	2.58	-	
V_F	Diode Forward Voltage	V_{GE}=0V, I_F=30A	T_J=25°C	-	1.88	2.4	V
			T_J=125°C	-	1.97	-	
			T_J=150°C	-	1.94	-	
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	V_{CE}=5V, I_C=1mA		-	4.6	-	V
I_{CES}	Zero Gate Voltage Collector Current	V_{CE}=650V, V_{GE}=0V	T_J=25°C	-	-	10	µA
			T_J=125°C	-	-	1000	
			T_J=150°C	-	-	5000	
I_{GES}	Gate-Emitter leakage current	V_{CE}=0V, V_{GE}=±30V		-	-	±100	nA
g_{FS}	Forward Transconductance	V_{CE}=20V, I_C=60A		-	33	-	S
DYNAMIC PARAMETERS							
C_{ies}	Input Capacitance	V_{GE}=0V, V_{CC}=25V, f=1MHz		-	2100	-	pF
C_{oes}	Output Capacitance			-	185	-	pF
C_{res}	Reverse Transfer Capacitance			-	65	-	pF
Q_g	Total Gate Charge	V_{GE}=15V, V_{CC}=520V, I_C=60A		-	84	-	nC
Q_{ge}	Gate to Emitter Charge			-	21	-	nC
Q_{gc}	Gate to Collector Charge			-	38	-	nC
R_g	Gate resistance	V_{GE}=0V, V_{CC}=0V, f=1MHz		-	15	-	Ω
SWITCHING PARAMETERS, (Load Inductive, T_J=25°C)							
$T_{D(on)}$	Turn-On DelayTime	T_J=25°C V_{GE}=15V, V_{CC}=400V, I_C=60A, R_G=5Ω		-	35	-	ns
T_r	Turn-On Rise Time			-	80	-	ns
$T_{D(off)}$	Turn-Off Delay Time			-	168	-	ns
T_f	Turn-Off Fall Time			-	76	-	ns
E_{on}	Turn-On Energy			-	2.36	-	mJ
E_{off}	Turn-Off Energy			-	1.17	-	mJ
E_{total}	Total Switching Energy			-	3.54	-	mJ
T_{rr}	Diode Reverse Recovery Time	T_J=25°C I_F=30A, dI/dt=200A/µs, V_{CC}=400V		-	318	-	ns
Q_{rr}	Diode Reverse Recovery Charge			-	0.8	-	µC
I_{rm}	Diode Peak Reverse Recovery Current			-	6.0	-	A
SWITCHING PARAMETERS, (Load Inductive, T_J=150°C)							
$T_{d(on)}$	Turn-On DelayTime	T_J=150°C V_{GE}=15V, V_{CC}=400V, I_C=60A, R_G=5Ω		-	33	-	ns
T_r	Turn-On Rise Time			-	80	-	ns
$T_{d(off)}$	Turn-Off Delay Time			-	195	-	ns
T_f	Turn-Off Fall Time			-	75	-	ns
E_{on}	Turn-On Energy			-	2.53	-	mJ
E_{off}	Turn-Off Energy			-	1.51	-	mJ
E_{total}	Total Switching Energy			-	4.04	-	mJ
T_{rr}	Diode Reverse Recovery Time	T_J=150°C I_F=30A, dI/dt=200A/µs, V_{CC}=400V		-	427	-	ns
Q_{rr}	Diode Reverse Recovery Charge			-	1.6	-	µC
I_{rm}	Diode Peak Reverse Recovery Current			-	7.5	-	A

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

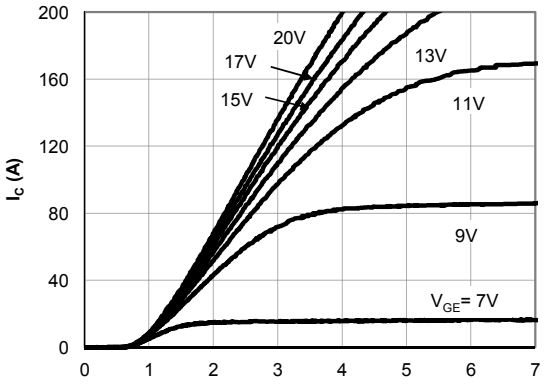

Figure 1: Output Characteristic (T_j=25°C)

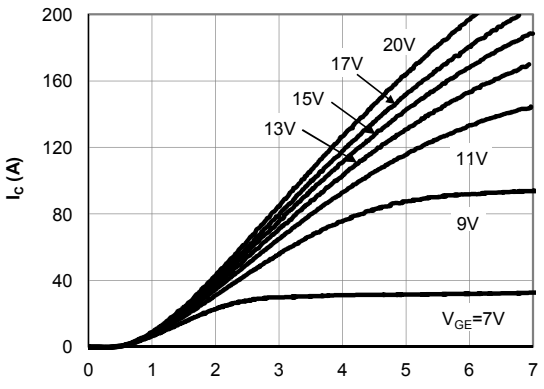

Figure 2: Output Characteristic (T_j=150°C)

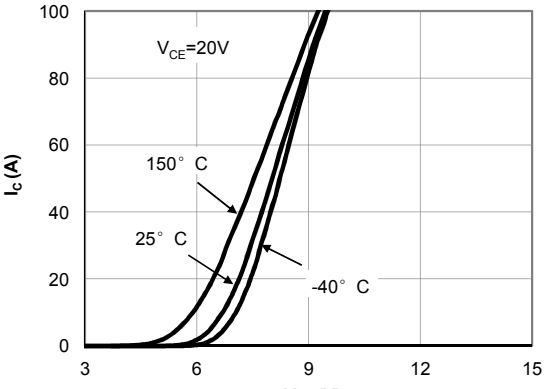

Figure 3: Transfer Characteristic

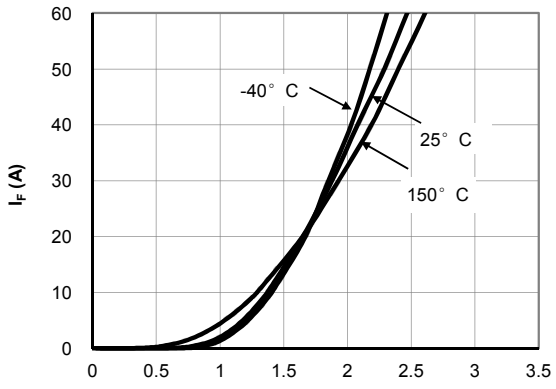

Figure 4: Diode Characteristic

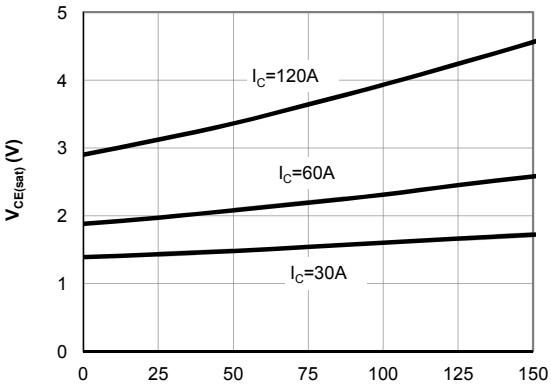

Figure 5: Collector-Emitter Saturation Voltage vs. Junction Temperature

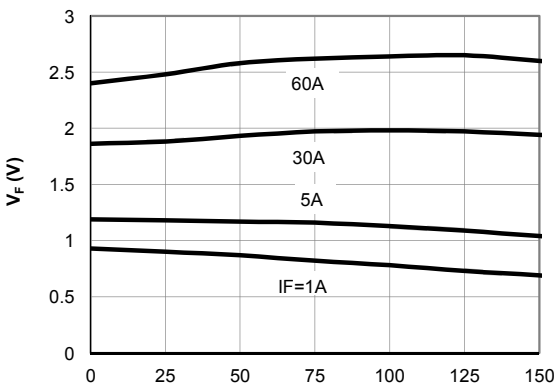

Figure 6: Diode Forward voltage vs. Junction Temperature

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

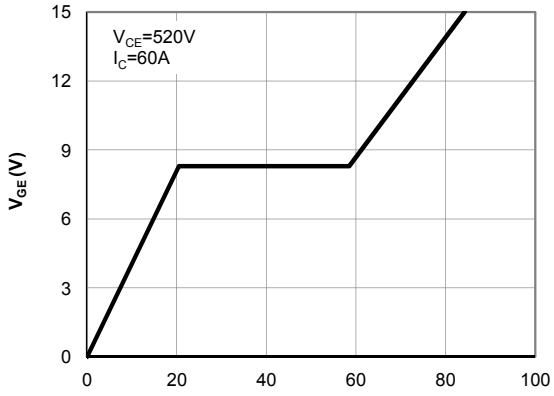

Figure 7: Gate-Charge Characteristics

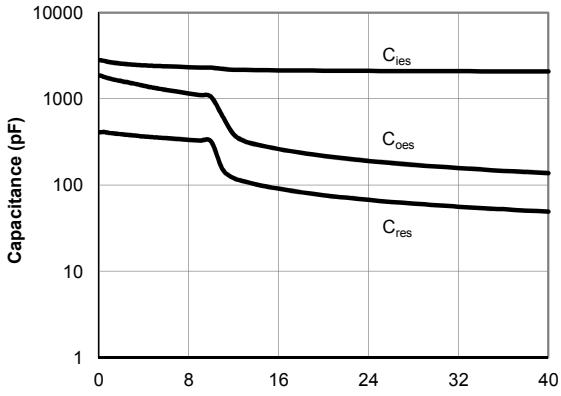

Figure 8: Capacitance Characteristic

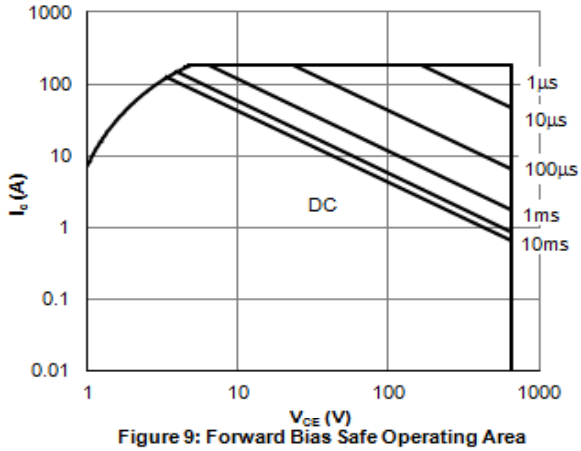

Figure 9: Forward Bias Safe Operating Area
(T_C=25°C, V_{GE}=15V)

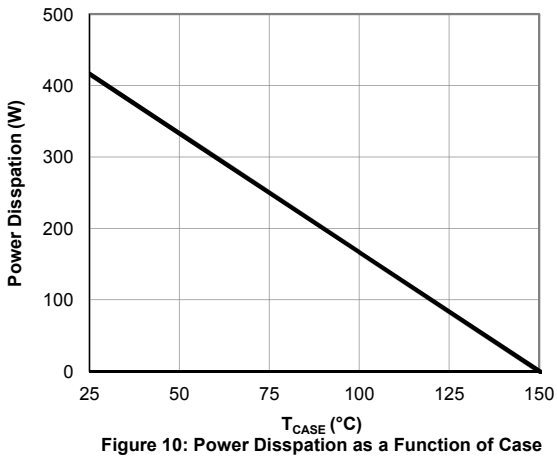

Figure 10: Power Disspation as a Function of Case

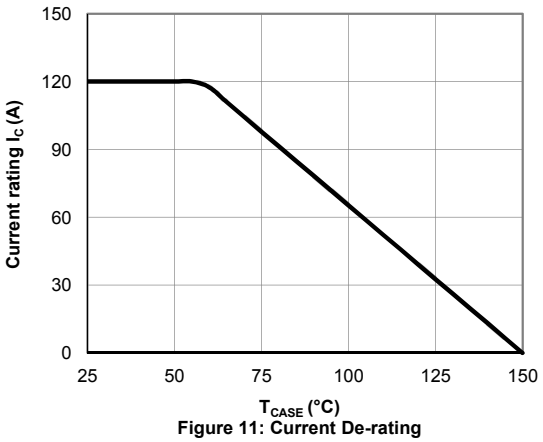

Figure 11: Current De-rating

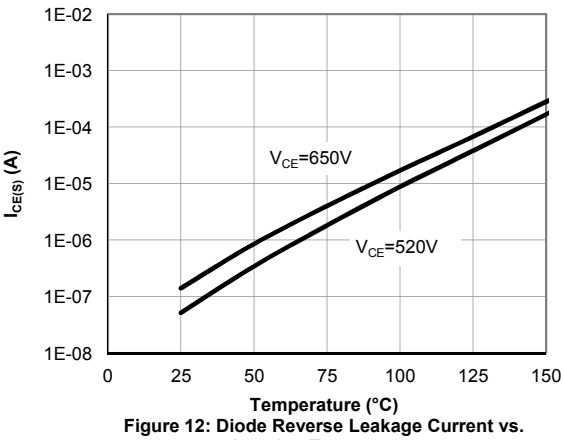

Figure 12: Diode Reverse Leakage Current vs. Junction Temperature

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

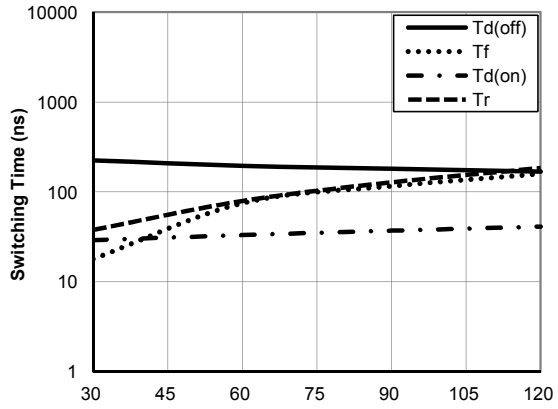

Figure 13: Switching Time vs. I_C
(T_j=150°C, V_{GE}=15V, V_{CE}=400V, R_g=5Ω)

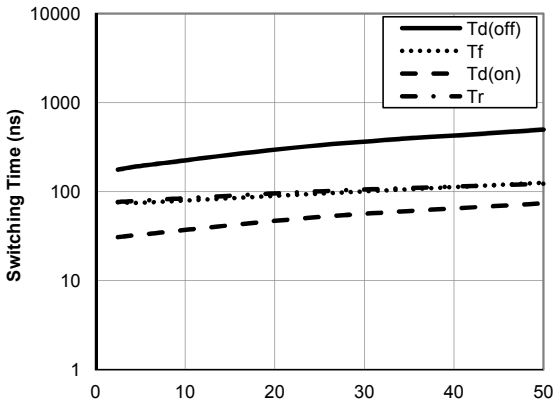

Figure 14: Switching Time vs. R_g
(T_j=150°C, V_{GE}=15V, V_{CE}=400V, I_C=60A)

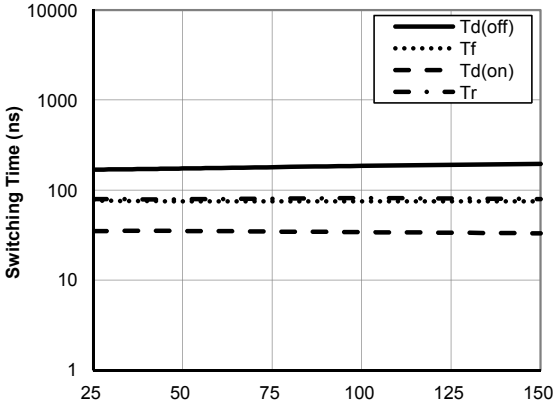

Figure 15: Switching Time vs.T_j
(V_{GE}=15V, V_{CE}=400V, I_C=40A, R_g=5Ω)

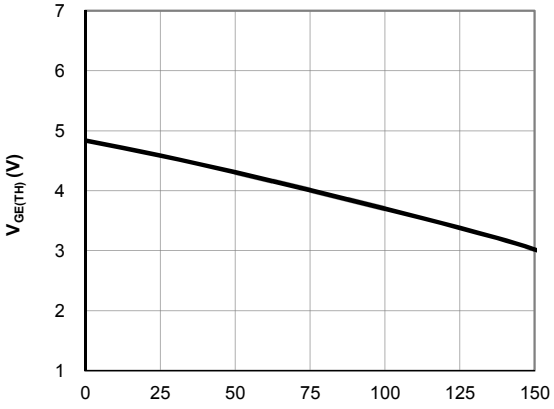

Figure 16: $V_{GE(TH)}$ vs. T_j

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

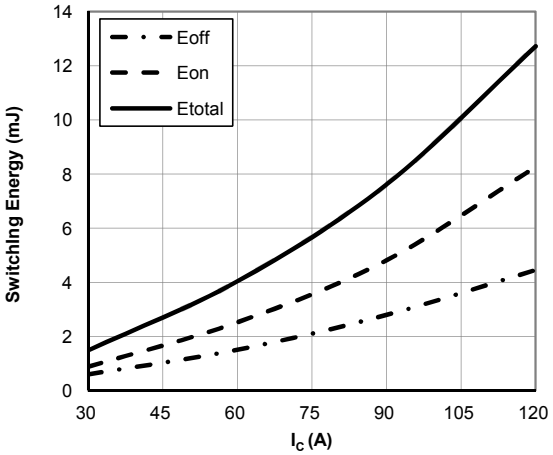

Figure 17: Switching Loss vs. I_C
(T_j=150°C, V_{GE}=15V, V_{CE}=400V, R_g=5Ω)

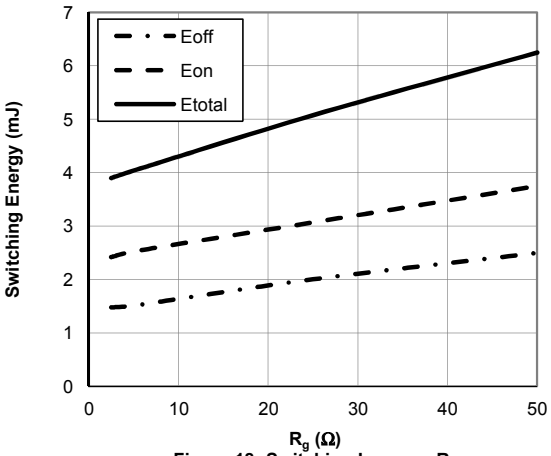

Figure 18: Switching Loss vs. R_g
(T_j=150°C, V_{GE}=15V, V_{CE}=400V, I_C=60A)

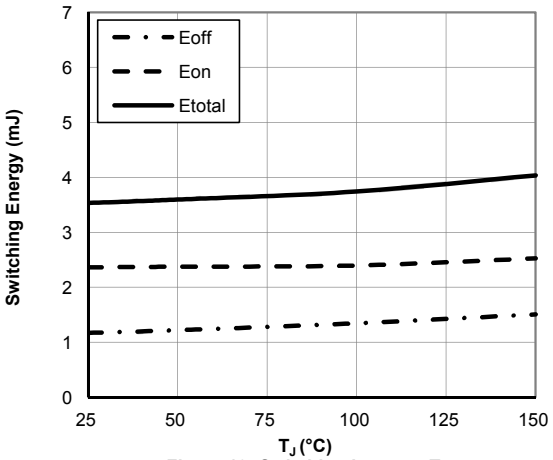

Figure 19: Switching Loss vs. T_j
(V_{GE}=15V, V_{CE}=400V, I_C=60A, R_g=5Ω)

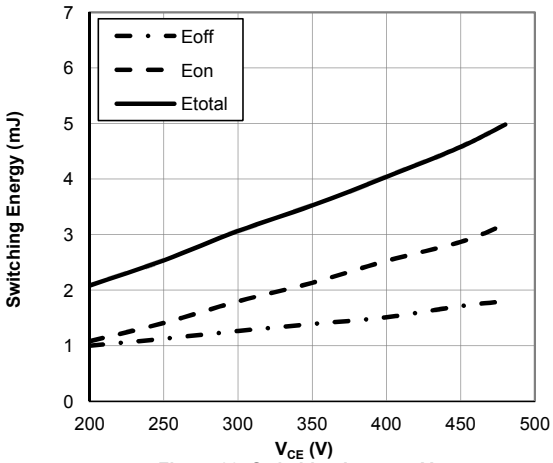

Figure 20: Switching Loss vs. V_{CE}
(T_j=150°C, V_{GE}=15V, I_C=60A, R_g=5Ω)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

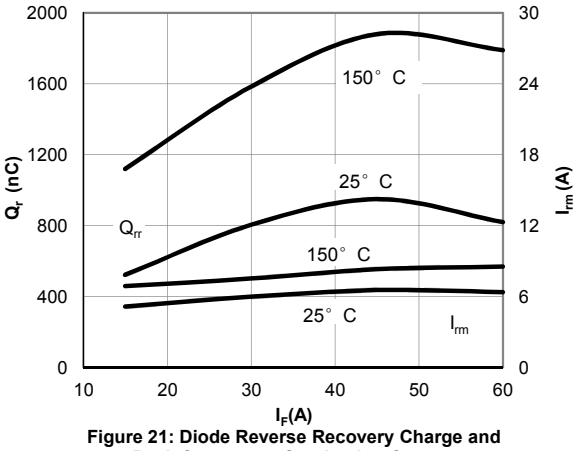

Figure 21: Diode Reverse Recovery Charge and Peak Current vs. Conduction Current (V_{GE}=15V, V_{CE}=400V, di/dt=200A/µs)

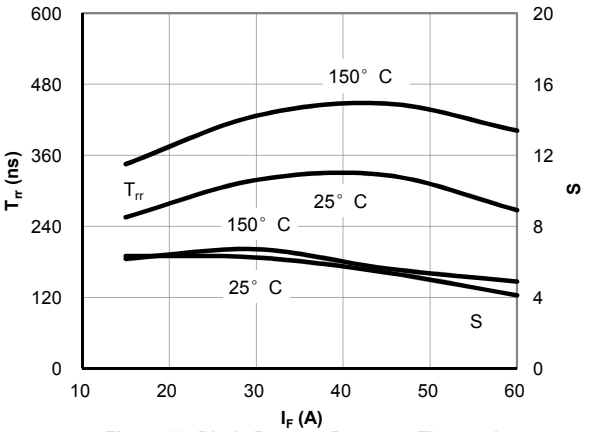

Figure 22: Diode Reverse Recovery Time and Softness Factor vs. Conduction Current (V_{GE}=15V, V_{CE}=400V, di/dt=200A/µs)

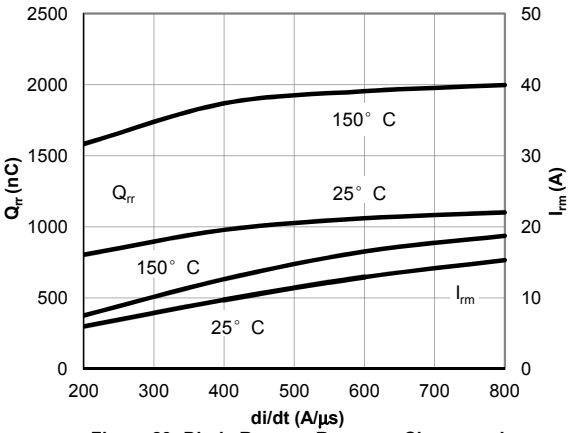

Figure 23: Diode Reverse Recovery Charge and Peak Current vs. di/dt (V_{GE}=15V, V_{CE}=400V, I_F=30A)

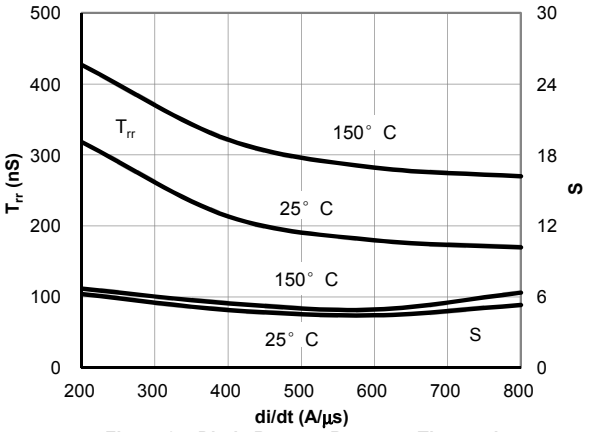

Figure 24: Diode Reverse Recovery Time and Softness Factor vs. di/dt (V_{GE}=15V, V_{CE}=400V, I_F=30A)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

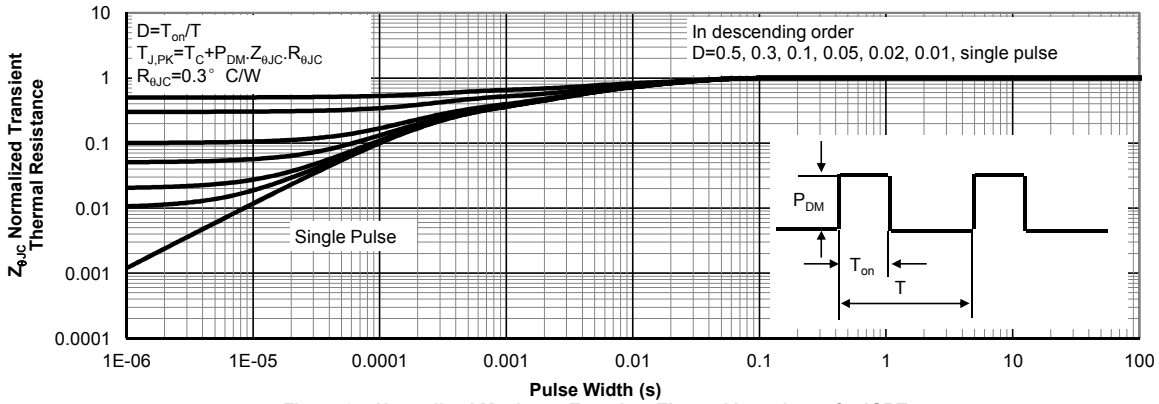

Figure 25: Normalized Maximum Transient Thermal Impedance for IGBT

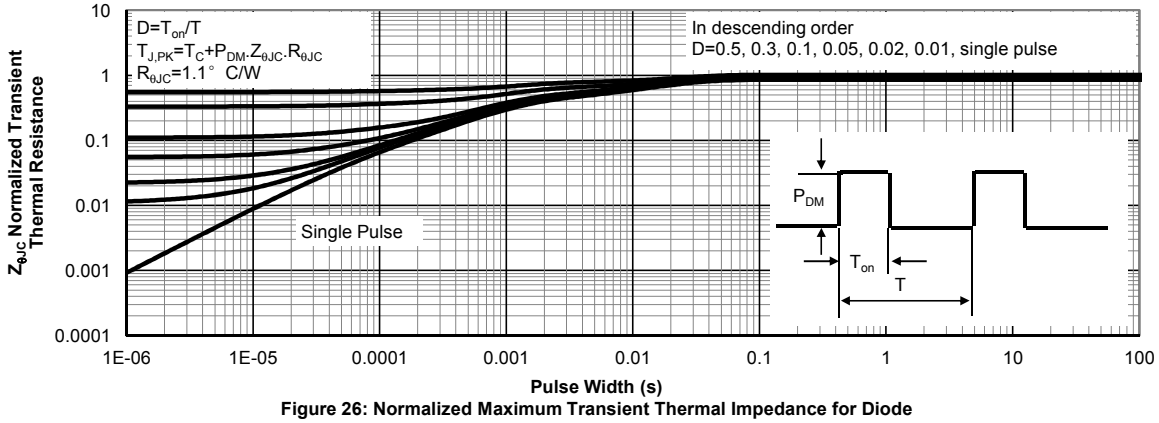

Figure 26: Normalized Maximum Transient Thermal Impedance for Diode

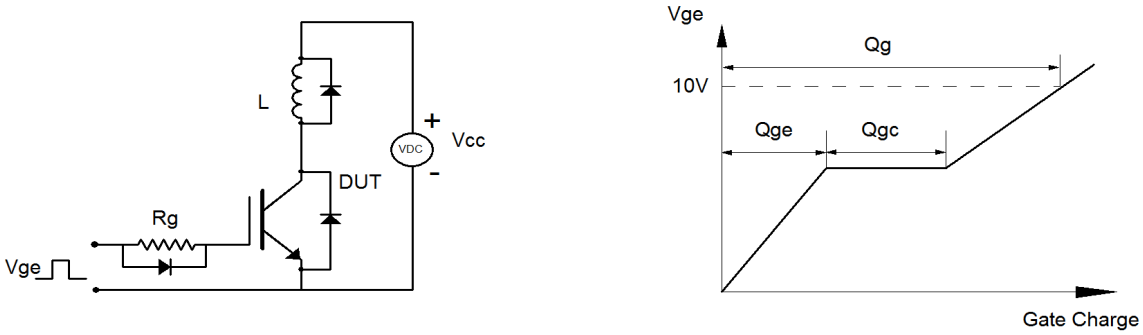

Figure A: Gate Charge Test Circuit & Waveforms

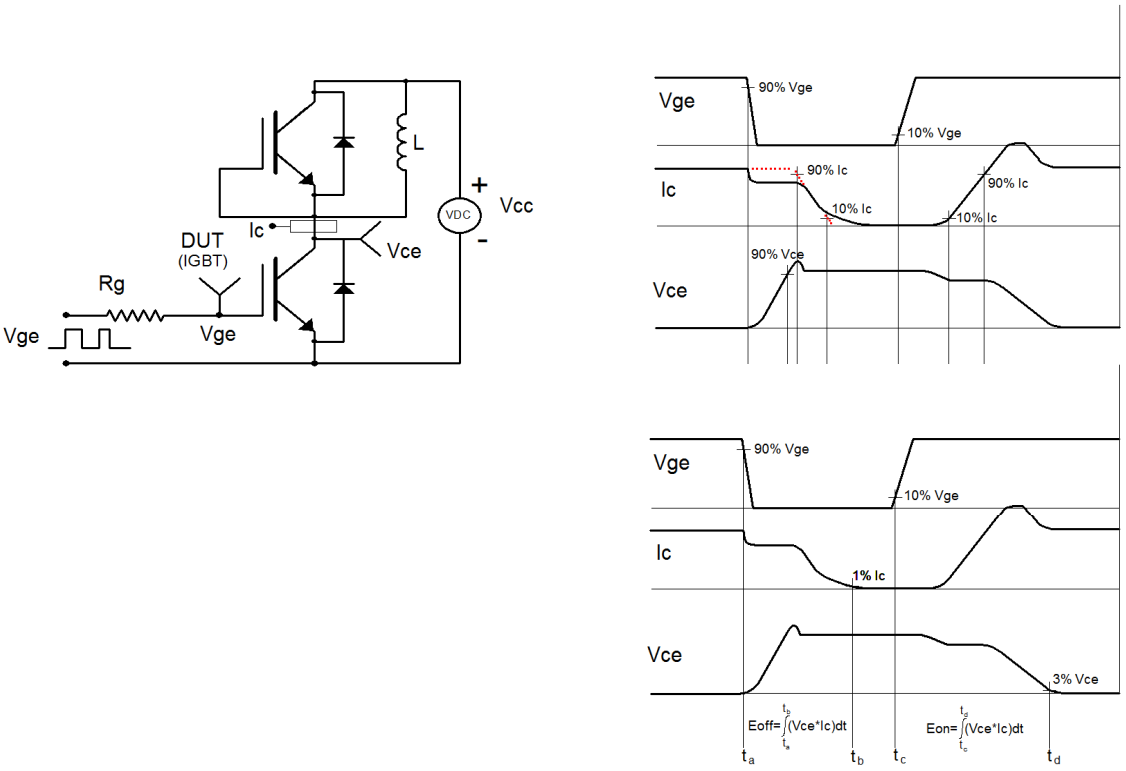

Figure B: Inductive Switching Test Circuit & Waveforms

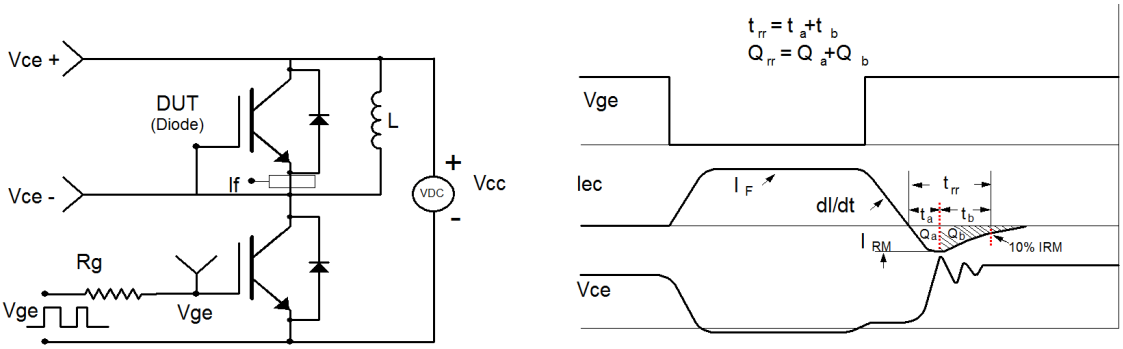

Figure C: Diode Recovery Test Circuit & Waveforms